

Octal Bus Buffer

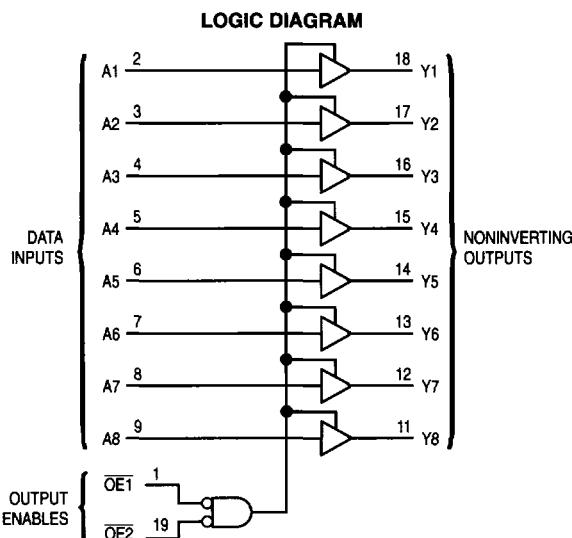
The MC74VHCT541A is an advanced high speed CMOS octal bus buffer fabricated with silicon gate CMOS technology. It achieves high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

The MC74VHCT541A is a noninverting, 3-state, buffer/line driver/line receiver. When either \overline{OE}_1 or \overline{OE}_2 is high, the terminal outputs are in the high impedance state.

The VHCT inputs are compatible with TTL levels. This device can be used as a level converter for interfacing 3.3V to 5.0V, because it has full 5V CMOS level output swings.

The VHCT541A input and output (when disabled) structures provide protection when voltages between 0V and 5.5V are applied, regardless of the supply voltage. These input and output structures help prevent device destruction caused by supply voltage – input/output voltage mismatch, battery backup, hot insertion, etc.

- High Speed: $t_{PD} = 5.4\text{ns}$ (Typ) at $V_{CC} = 5\text{V}$
- Low Power Dissipation: $I_{CC} = 4\mu\text{A}$ (Max) at $T_A = 25^\circ\text{C}$
- TTL-Compatible Inputs: $V_{IL} = 0.8\text{V}$; $V_{IH} = 2.0\text{V}$
- Power Down Protection Provided on Inputs and Outputs
- Balanced Propagation Delays
- Designed for 4.5V to 5.5V Operating Range
- Low Noise: $V_{OLP} = 1.6\text{V}$ (Max)
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 300mA
- ESD Performance: HBM > 2000V; Machine Model > 200V
- Chip Complexity: 134 FETs or 33.5 Equivalent Gates



MC74VHCT541A



DW SUFFIX
20-LEAD SOIC WIDE PACKAGE
CASE 751D-04



DT SUFFIX
20-LEAD TSSOP PACKAGE
CASE 948E-02



M SUFFIX
20-LEAD SOIC EIAJ PACKAGE
CASE 967-01

| ORDERING INFORMATION | |
|----------------------|-----------|
| MC74VHCTXXXADW | SOIC WIDE |
| MC74VHCTXXXADT | TSSOP |
| MC74VHCTXXXAM | SOIC EIAJ |

PIN ASSIGNMENT

| | | | |
|-------------------|-----|----|-------------------|
| \overline{OE}_1 | 1 • | 20 | V _{CC} |
| A1 | 2 | 19 | \overline{OE}_2 |
| A2 | 3 | 18 | Y1 |
| A3 | 4 | 17 | Y2 |
| A4 | 5 | 16 | Y3 |
| A5 | 6 | 15 | Y4 |
| A6 | 7 | 14 | Y5 |
| A7 | 8 | 13 | Y6 |
| A8 | 9 | 12 | Y7 |
| GND | 10 | 11 | Y8 |

FUNCTION TABLE

| Inputs | | | Output Y |
|-------------------|-------------------|---|----------|
| \overline{OE}_1 | \overline{OE}_2 | A | |
| L | L | L | L |
| L | L | H | H |
| H | X | X | Z |
| X | H | X | Z |



MAXIMUM RATINGS*

| Symbol | Parameter | Value | Unit |
|------------------|--|--|------|
| V _{CC} | DC Supply Voltage | – 0.5 to + 7.0 | V |
| V _{in} | DC Input Voltage | – 0.5 to + 7.0 | V |
| V _{out} | DC Output Voltage Outputs in 3-State High or Low State | – 0.5 to + 7.0 – 0.5 to V _{CC} + 0.5 | V |
| I _{IK} | Input Diode Current | – 20 | mA |
| I _{OK} | Output Diode Current (V _{OUT} < GND; V _{OUT} > V _{CC}) | ± 20 | mA |
| I _{out} | DC Output Current, per Pin | ± 25 | mA |
| I _{CC} | DC Supply Current, V _{CC} and GND Pins | ± 75 | mA |
| P _D | Power Dissipation in Still Air, SOIC Packages† TSSOP Package† | 500 450 | mW |
| T _{stg} | Storage Temperature | – 65 to + 150 | °C |

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range GND ≤ (V_{in} or V_{out}) ≤ V_{CC}.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

* Absolute maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute-maximum-rated conditions is not implied.

†Derating — SOIC Packages: – 7 mW/°C from 65° to 125°C
TSSOP Package: – 6.1 mW/°C from 65° to 125°C

RECOMMENDED OPERATING CONDITIONS

| Symbol | Parameter | Min | Max | Unit |
|---------------------------------|--|--------|------------------------|------|
| V _{CC} | DC Supply Voltage | 4.5 | 5.5 | V |
| V _{in} | DC Input Voltage | 0 | 5.5 | V |
| V _{out} | DC Output Voltage Outputs in 3-State High or Low State | 0 0 | 5.5 V _{CC} | V |
| T _A | Operating Temperature | – 40 | + 85 | °C |
| t _r , t _f | Input Rise and Fall Time V _{CC} = 5.0V ± 0.5V | 0 | 20 | ns/V |

DC ELECTRICAL CHARACTERISTICS

| Symbol | Parameter | Test Conditions | V _{CC} V | T _A = 25°C | | | T _A = – 40 to 85°C | | Unit |
|-----------------|---|---|----------------------|-----------------------|-----|--------|-------------------------------|-------|------|
| | | | | Min | Typ | Max | Min | Max | |
| V _{IH} | Minimum High-Level Input Voltage | | 4.5 to 5.5 | 2.0 | | | 2.0 | | V |
| V _{IL} | Maximum Low-Level Input Voltage | | 4.5 to 5.5 | | | | 0.8 | | V |
| V _{OH} | Minimum High-Level Output Voltage V _{in} = V _{IH} or V _{IL} | I _{OH} = – 50µA | 4.5 | 4.4 | 4.5 | | 4.4 | | V |
| | | I _{OH} = – 8mA | 4.5 | 3.94 | | | 3.80 | | |
| V _{OL} | Maximum Low-Level Output Voltage V _{in} = V _{IH} or V _{IL} | I _{OL} = 50µA | 4.5 | | 0.0 | 0.1 | | 0.1 | V |
| | | I _{OL} = 8mA | 4.5 | | | 0.36 | | 0.44 | |
| I _{in} | Maximum Input Leakage Current | V _{in} = 5.5 V or GND | 0 to 5.5 | | | ± 0.1 | | ± 1.0 | µA |
| I _{OZ} | Maximum 3-State Leakage Current | V _{in} = V _{IL} or V _{IH} V _{out} = V _{CC} or GND | 5.5 | | | ± 0.25 | | ± 2.5 | µA |
| I _{CC} | Maximum Quiescent Supply Current | V _{in} = V _{CC} or GND | 5.5 | | | 4.0 | | 40.0 | µA |

DC ELECTRICAL CHARACTERISTICS

| Symbol | Parameter | Test Conditions | V _{CC} V | T _A = 25°C | | | T _A = -40 to 85°C | | Unit |
|------------------|--------------------------|--|----------------------|-----------------------|-----|------|------------------------------|------|------|
| | | | | Min | Typ | Max | Min | Max | |
| I _{CCT} | Quiescent Supply Current | Per Input: V _{IN} = 3.4V Other Input: V _{CC} or GND | 5.5 | | | 1.35 | | 1.50 | mA |
| I _{OPD} | Output Leakage Current | V _{OUT} = 5.5V | 0 | | | 0.5 | | 5.0 | μA |

AC ELECTRICAL CHARACTERISTICS (Input t_r = t_f = 3.0ns)

| Symbol | Parameter | Test Conditions | T _A = 25°C | | | T _A = -40 to 85°C | | Unit |
|--|---|--|-----------------------|------------|--------------|------------------------------|--------------|------|
| | | | Min | Typ | Max | Min | Max | |
| t _{PLH} , t _{PHL} | Maximum Propagation Delay, A to Y | V _{CC} = 5.0 ± 0.5V C _L = 15pF C _L = 50pF | | 5.0 5.5 | 6.9 7.9 | 1.0 1.0 | 8.0 9.0 | ns |
| t _{PZL} , t _{PZH} | Output Enable Time, OE to Y | V _{CC} = 5.0 ± 0.5V R _L = 1kΩ C _L = 50pF | | 8.3 8.8 | 11.3 12.3 | 1.0 1.0 | 13.0 14.0 | ns |
| t _{PLZ} , t _{PHZ} | Output Disable Time, OE to Y | V _{CC} = 5.0 ± 0.5V R _L = 1kΩ C _L = 50pF | | 9.4 | 11.9 | 1.0 | 13.5 | ns |
| t _{OSLH} , t _{OSHL} | Output to Output Skew | V _{CC} = 5.0 ± 0.5V (Note 1.) C _L = 50pF | | | 1.0 | | 1.0 | ns |
| C _{in} | Maximum Input Capacitance | | | 4 | 10 | | 10 | pF |
| C _{out} | Maximum Three-State Output Capacitance (Output in High Impedance State) | | | 9 | | | | pF |

| CPD | Power Dissipation Capacitance (Note 2.) | Typical @ 25°C, V _{CC} = 5.0V | | pF |
|-----|---|--|--|----|
| | | 19 | | |

1. Parameter guaranteed by design. t_{OSLH} = |t_{PLHm} - t_{PLLn}|, t_{OSHL} = |t_{PHLm} - t_{PHLn}|.
2. CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: I_{CC(OPR)} = CPD • V_{CC} • f_{in} + I_{CC}/8 (per bit). CPD is used to determine the no-load dynamic power consumption; P_D = CPD • V_{CC}² • f_{in} + I_{CC} • V_{CC}.

NOISE CHARACTERISTICS (Input t_r = t_f = 3.0ns, C_L = 50pF, V_{CC} = 5.0V)

| Symbol | Parameter | T _A = 25°C | | | Unit |
|------------------|--|-----------------------|------|--|------|
| | | Typ | Max | | |
| V _{OLP} | Quiet Output Maximum Dynamic V _{OL} | 1.2 | 1.6 | | V |
| V _{OVL} | Quiet Output Minimum Dynamic V _{OL} | -1.2 | -1.6 | | V |
| V _{IHD} | Minimum High Level Dynamic Input Voltage | | 2.0 | | V |
| V _{ILD} | Maximum Low Level Dynamic Input Voltage | | 0.8 | | V |

SWITCHING WAVEFORMS

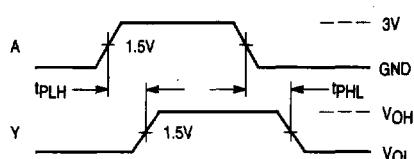


Figure 1.

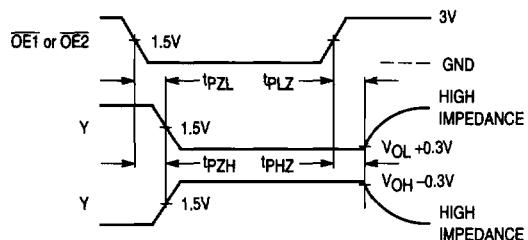
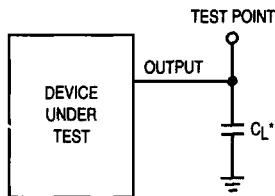
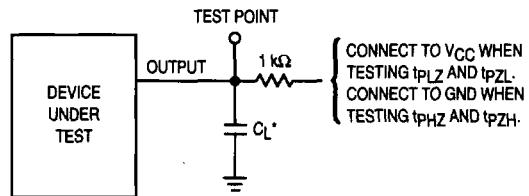


Figure 2.

TEST CIRCUITS



* Includes all probe and jig capacitance



* Includes all probe and jig capacitance

Figure 3. Test Circuit

Figure 4. Test Circuit